

Amendments to the Claims

1. (Currently Amended) A semiconductor device comprising:
signal lines over which signals are transferred; and
a drive circuit driving the signal lines in operating modes, the operating modes including a dynamic operation mode in which the signal lines are precharged prior to transfer of the signals over said signal lines, and a static operation mode in which the signal lines are not precharged prior to transfer of the signals over said signal lines.
2. (Original) The semiconductor device as claimed in claim 1, further comprising a memory cell array to which the signal lines are connected, data read from the memory cell array being transferred over the signal lines.
3. (Original) The semiconductor device as claimed in claim 1, further comprising a test-dedicated line,
a predetermined test of the semiconductor device being performed using the test-dedicated line and the signal lines.
4. (Original) The semiconductor device as claimed in claim 3, further comprising a circuit receiving the signal lines at inputs thereof and outputting a test result, said test result and a logic level of the test-dedicated line forming a result of the predetermined test.

5. (Original) The semiconductor device as claimed in claim 3, further comprising a precharge circuit precharging the signal lines and the test-dedicated line.

6. (Original) The semiconductor device as claimed in claim 5, the precharge circuit precharging the signal lines and the test-dedicated line in the dynamic operation mode only.